

Amendments to the Specification:

Please amend the specification as follows:

Please replace the second full paragraph beginning on page 40 and ending on page 41 (Paragraph [0107]) with the amended paragraph below:

Further, FIG. 13 shows an explanatory flowchart of another variant of the first film thickness measurement point extraction method. This variant enables extracting a film thickness measurement point without registering a pattern beforehand. That is, a film thickness measurement point is determined along FIG. 13. When step S4 of FIG. 6 for determining film thickness measurement points starts, the measurement point extraction portion 32 uses the image recognition technology to extract a pattern Q which provides a repetition unit from a measured image picked up at the photo-detector 26 (step S41); detects a center (or a predetermined position such as a geometrical gravity center position of the unit pattern Q) , and sets the film thickness measurement point P to that point (step S42). When the film thickness measurement point P is thus determined, the measurement point extraction portion 32 decides whether the film thickness measurement point P has been determined properly (step S43). If it decides that the film thickness measurement point P has not properly determined (NG at step S43), it takes in an image of the measurement target 36 again (Step S44) and extracts the unit pattern Q and determines the film thickness measurement point P again (steps S33, S41-S42). If it decides that the film thickness measurement point P has been determined properly (OK at step S43), on the other hand, steps of S5 and the subsequent of FIG. 6 are performed, thereby measuring a film thickness of the measurement target.